Silicon N-Channel/P-Channel Power MOS FET Array

HITACHI

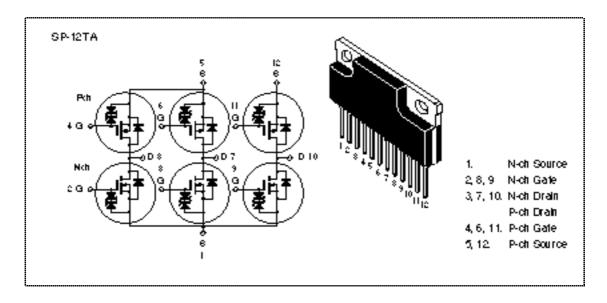
Application

High speed power switching

Features

- Low on-resistance
- Low drive current
- High speed switching
- High density mounting

Outline





Absolute Maximum Ratings $(Ta = 25^{\circ}C)$

	Symbol		js –	
Item			Pch	Unit
Drain to source voltage	V _{DSS}	60	-60	V
Gate to source voltage	V _{GSS}	±20	±20	V
Drain current	I _D	7	- 7	A
Drain peak current	^I D(pulse) ^{*1}	28	-28	A
Reverse drain current	I _{DR}	7	- 7	Α
Channel dissipation	Pch* ²	42		W
Channel dissipation	Pch* ²	4.8		W
Channel temperature	Tch	150		°C
Storage temperature	Tstg	–55 to		°C

Notes: 1. PW 10 µs, duty cycle 1%

2. Value at 6 Drive operation



Electrical Characteristics N Channel (Ta = 25°C)

Item	Symbol	Min	Тур	Max	Unit	Test conditions
Drain to source breakdown voltage	V _{(BR)DS} S	60	_	_	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	^V (BR)GS S	±20	_	<u> </u>	V	I _G = ±100 μA, V _{DS} = 0
Gate to source leak current	I _{GSS}		<u>—</u>	±10	μΑ	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I _{DSS}	—	—	250	μΑ	$V_{DS} = 50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	VGS(off)	0.5	_	1.5	V	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA}$
Static drain to source on state	R _{DS(on)}	—	0.14	0.2		I _D = 4 A
resistance						$V_{GS} = 4 V^{*1}$
			0.22	0.5		I _D = 2 A
						$V_{GS} = 2.5 V^{*1}$
Forward transfer admittance	у _{fs}	4.0	6.5	<u> </u>	S	I _D = 4 A
						$V_{DS} = 10 \text{ V}^{*1}$
Input capacitance	Ciss		500	<u>—</u>	pF	V _{DS} = 10 V
Output capacitance	Coss		240	<u>—</u>	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	—	30	_	pF	f = 1 MHz
Turn-on delay time	^t d(on)	_	15	_	ns	V _{GS} = 10 V, I _D = 4 A
Rise time	t _r		90	<u>—</u>	ns	 R _L = 7.5
Turn-off delay time	^t d(off)		110	<u>—</u>	ns	•
Fall time	t _f	—	250	_	ns	
Body to drain diode forward voltage	V _{DF}	—	1.0	—	V	I _F = 7 A, V _{GS} = 0
Body to drain diode reverse recovery time	^t rr		170	<u> </u>	ns	$I_F = 7 \text{ A, V}_{GS} = 0$ diF/dt = 50 A/ μ s

Note: 1. Pulse Test

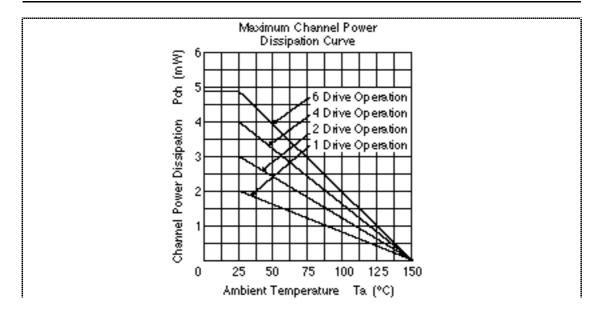


Electrical Characteristics P Channel (Ta = 25°C)

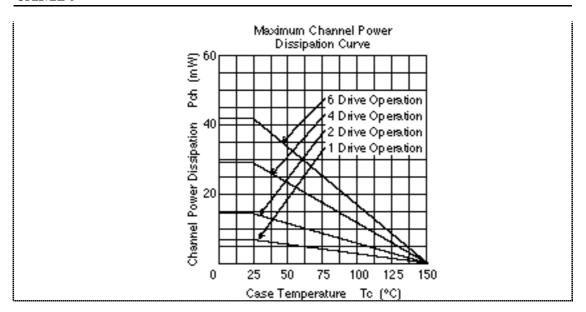
Item	Symbol	Min	Тур	Max	Unit	Test conditions
Drain to source breakdown voltage	V _{(BR)DS} S	-60	_	_	V	$I_D = -10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	^V (BR)GS S	±20	<u>—</u>		V	I _G = ±100 μA, V _{DS} = 0
Gate to source leak current	l _{GSS}	<u>—</u>	<u>—</u>	±10	μΑ	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I _{DSS}	<u>—</u>	<u>—</u>	-250	μΑ	$V_{DS} = -50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	VGS(off)	-0.5	—	-1.5	V	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$
Static drain to source on state	R _{DS(on)}	<u>—</u>	0.12	0.16	•••••••••••	I _D = -4 A
resistance						$V_{GS} = -4 V^{*1}$
		<u>—</u>	0.16	0.3	•••••••••••	I _D = -2 A
						$V_{GS} = -2.5 \text{ V}^{*1}$
Forward transfer admittance	у _{fs}	5.0	8.0	<u>—</u>	S	I _D = -4 A
						$V_{DS} = -10 \text{ V}^{*1}$
Input capacitance	Ciss		1450		pF	V _{DS} = -10 V
Output capacitance	Coss	_	590	—	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	120	_	pF	f = 1 MHz
Turn-on delay time	^t d(on)	_	15	_	ns	$V_{GS} = -10 \text{ V}, I_D = -4 \text{ A}$
Rise time	t _r	_	75	—	ns	R _L = 7.5
Turn-off delay time	^t d(off)	_	240	_	ns	
Fall time	t _f	_	180	_	ns	
Body to drain diode forward voltage	V _{DF}		-1.0		V	I _F = -7 A, V _{GS} = 0
Body to drain diode reverse	t _{rr}		210		ns	$I_F = -7 \text{ A}, V_{GS} = 0$
recovery time						diF/dt = 50 A/µs

Note: 1. Pulse Test











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